TEXAS INSTRUMENTS
Data sheet acquired from Harris Semiconductor
SCHS104C – Revised October 2003

CD40174B Types

CMOS Hex 'D'-Type Flip-Flop

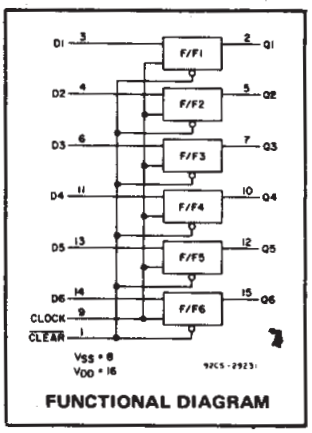
High-Voltage Types (20-Volt Rating)

■ CD40174B consists of six identical 'D'-type flip-flops having independent DATA inputs. The CLOCK and $\overline{\text{CLEAR}}$ inputs are common to all six units. Data is transferred to the Q outputs on the positive-going transition of the clock pulse. All six flip-flops are simultaneously reset by a low level on the $\overline{\text{CLEAR}}$ input.

The CD40174B types are supplied in 16-lead hermetic dual-in-line ceramic packages (F3A suffix), 16-lead dual-in-line plastic packages (E suffix), 16-lead small-outline packages (M, M96, MT, and NSR suffixes), and 16-lead thin shrink small-outline packages (PW and PWR suffixes).

Features:

- 5-V, 10-V, and 15-V parametric rating
- Standardized symmetrical output characteristics
- 100% tested for quiescent current at 20 V
- Maximum input current of 1 μA at 18 V over full package-temperature range; 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at V_{DD} = 5 V; 2 V at V_{DD} = 10 V; 2.5 V at V_{DD} = 15 V
- Meets all requirements of JEDEC Tentative Standard No. 13A, "Standard Specifications for Description of 'B' Series CMOS Devices"



FUNCTIONAL DIAGRAM

Applications:

- Shift Registers
- Buffer/Storage Registers
- Pattern Generators

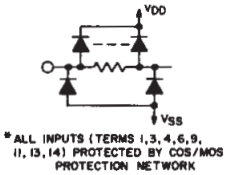
MAXIMUM RATINGS, *Absolute-Maximum Values:*

DC SUPPLY-VOLTAGE RANGE, (V_{DD})
Voltages referenced to V_{SS} Terminal) ..... −0.5V to +20V
INPUT VOLTAGE RANGE, ALL INPUTS ..... −0.5V to V_{DD} +0.5V
DC INPUT CURRENT, ANY ONE INPUT ..... ±10mA
POWER DISSIPATION PER PACKAGE (P_D):
For T_A = −55°C to +100°C 500mW
For T_A = +100°C to +125°C ..... Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR
FOR T_A = FULL PACKAGE-TEMPERATURE RANGE (All Package Types)..... 100mW
OPERATING-TEMPERATURE RANGE (T_A) .....−55°C to +125°C
STORAGE TEMPERATURE RANGE (T_{stg}) .....−65°C to +150°C
LEAD TEMPERATURE (DURING SOLDERING):
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max ..... +265°C

TRUTH TABLE FOR 1 OF 6 FLIP-FLOPS

INPUTS			OUTPUT
CLOCK	DATA	$\overline{\text{CLEAR}}$	Q
⌐¯	0	1	0
⌐¯	1	1	1
¯⌐	X	1	NC
X	X	0	0

1 = High Level X = Don't Care
0 = Low Level NC = No Change



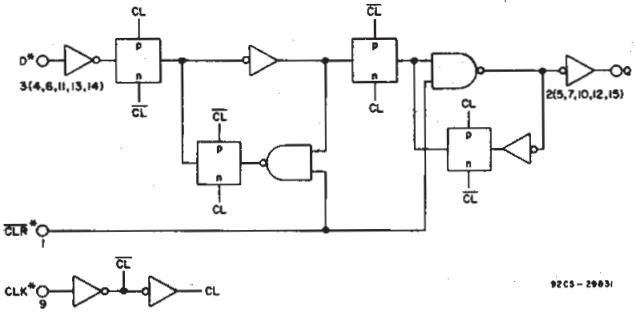


Fig. 1 – Logic diagram (1 of 6 flip-flops).

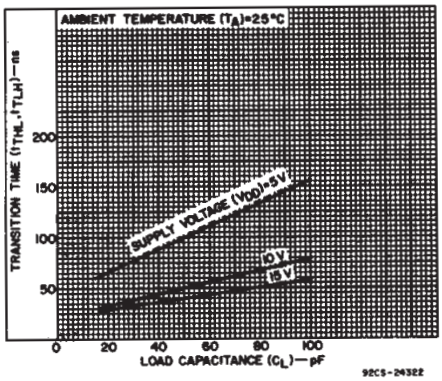
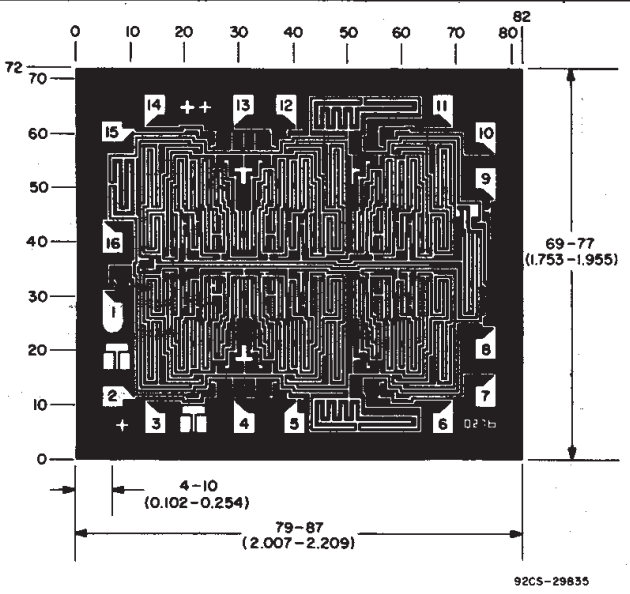


Fig. 2– Typical transition time as a function of load capacitance.

RECOMMENDED OPERATING CONDITIONS at T_A = 25°C, Except as Noted.
For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	V_{DD} (V)	LIMITS		UNITS
		Min.	Max.	
Supply-Voltage Range (For T_A = Full Package-Temperature Range)	–	3	18	V
Data Setup Time, t_{SU}	5	40	–	ns
	10	20	–	
	15	10	–	
Data Hold Time, t_H	5	80	–	ns
	10	40	–	
	15	30	–	
Clock Input Frequency, f_{CL}	5	–	3.5	MHz
	10	dc	6	
	15		8	
Clock Input Rise or Fall Time, t_rCL, t_fCL	5	–	15	μs
	10	–	15	
	15	–	15	
Clock Input Pulse Width, t_{WL}, t_{WH}	5	130	–	ns
	10	60	–	
	15	40	–	
$\overline{\text{Clear}}$ Pulse Width, t_{WL}	5	100	–	ns
	10	50	–	
	15	40	–	
$\overline{\text{Clear}}$ Removal Time, t_{REM}	5	0	–	ns
	10	0	–	
	15	0	–	



Dimensions and pad layout for CD40174BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch).

The photographs and dimensions of each CMOS chip represent a chip when it is part of the wafer. When the wafer is separated into individual chips, the angle of cleavage may vary with respect to the chip face for different chips. The actual dimensions of the isolated chip, therefore, may differ slightly from the nominal dimensions shown. The user should consider a tolerance of −3 mils to +16 mils applicable to the nominal dimensions shown.

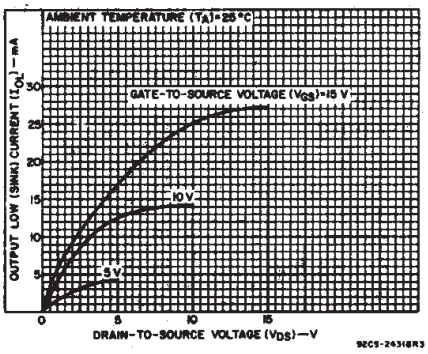


Fig. 3— Typical output low (sink) current characteristics.

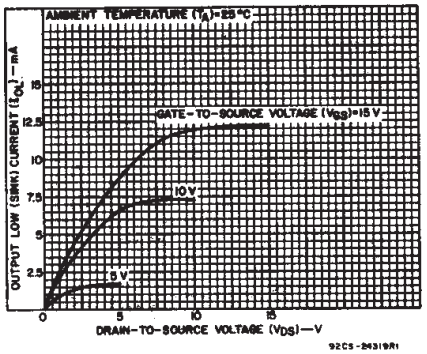


Fig. 4— Minimum output low (sink) current characteristics.

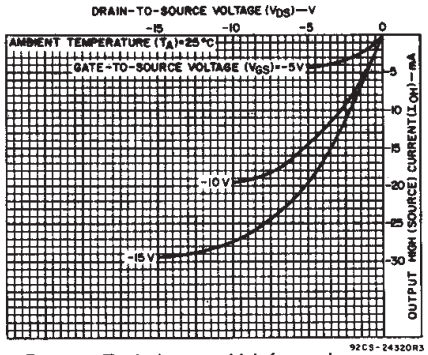


Fig. 5— Typical output high (source) current characteristics.

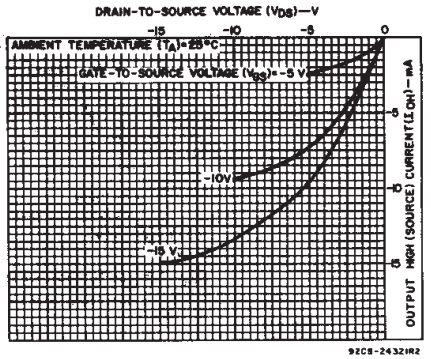


Fig. 6— Minimum output high (source) current characteristics.

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)							UNITS
	V_O (V)	V_{IN} (V)	V_{DD} (V)	−55	−40	+85	+125	+25 Min.	+25 Typ.	+25 Max.	
Quiescent Device Current, I_{DD} Max.	–	0,5	5	1	1	30	30	–	0.02	1	μA
	–	0,10	10	2	2	60	60	–	0.02	2	
	–	0,15	15	4	4	120	120	–	0.02	4	
	–	0,20	20	20	20	600	600	–	0.04	20	
Output Low (Sink) Current I_{OL} Min.	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1	–	mA
	0.5	0,10	10	1.6	1.5	1.1	0.9	1.3	2.6	–	
	1.5	0,15	15	4.2	4	2.8	2.4	3.4	6.8	–	
Output High (Source) Current, I_{OH} Min.	4.6	0,5	5	−0.64	−0.61	−0.42	−0.36	−0.51	−1	–	
	2.5	0,5	5	−2	−1.8	−1.3	−1.15	−1.6	−3.2	–	
	9.5	0,10	10	−1.6	−1.5	−1.1	−0.9	−1.3	−2.6		
	13.5	0,15	15	−4.2	−4	−2.8	−2.4	−3.4	−6.8		
Output Voltage: Low-Level, V_{OL} Max.	–	0,5	5	0.05				–	0	0.05	V
	–	0,10	10	0.05				–		0.05	
	–	0,15	15	0.05				–	0	0.05	
Output Voltage: High-Level, V_{OH} Min.	–	0,5	5	4.95				4.95	5	–	
	–	0,10	10	9.95				9.95	10	–	
	–	0,15	15	14.95				14.95	15	–	
Input Low Voltage, V_{IL} Max.	0.5,4.5	–	5	1.5				–	–	1.5	V
	1,9	–	10	3				–	–	3	
	1.5,13.5	–	15	4				–	–	4	
Input High Voltage, V_{IH} Min.	0.5,4.5	–	5	3.5				3.5	–	–	
	1,9	–	10	7				7	–	–	
	1.5,13.5	–	15	11				11	–	–	
Input Current I_{IN} Max.	–	0,18	18	±0.1	±0.1	±1	±1	–	$\pm 10^{-5}$	±0.1	μA

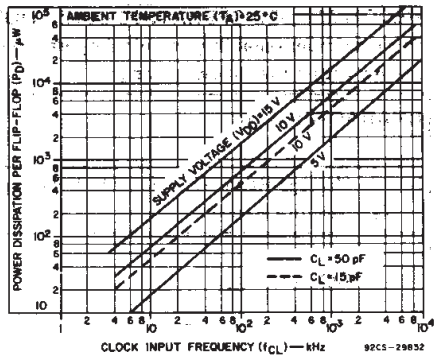


Fig. 7— Typical dynamic power dissipation as a function of CLOCK frequency.

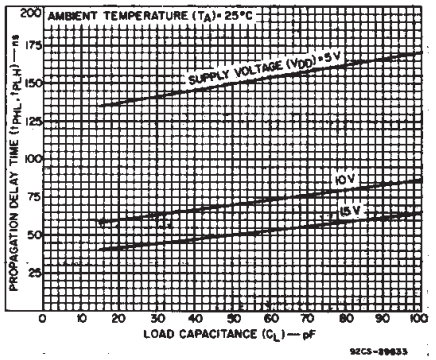


Fig. 8— Typical propagation delay time (CLOCK to OUTPUT) as a function of load capacitance.

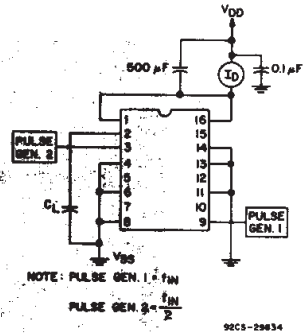


Fig. 9— Dynamic power dissipation test circuit.

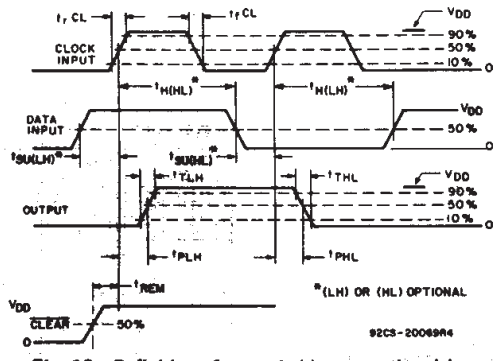


Fig. 10— Definition of setup, hold, propagation delay, and removal times.

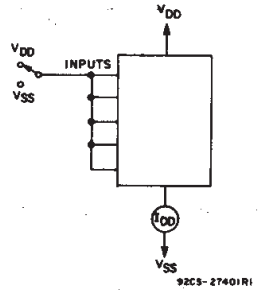


Fig. 11 — Quiescent device current test circuit.

DYNAMIC ELECTRICAL CHARACTERISTICS at T_A = 25°C;
Input t_r, t_f = 20 ns, C_L = 50 pF, R_L = 200 kΩ

CHARACTERISTIC	TEST CONDITIONS V_{DD} (V)	LIMITS			UNITS
		Min.	Typ.	Max.	
Propagation Delay Time Clock to Output, t_{PHL}, t_{PLH}	5	–	150	300	ns
	10	–	70	140	
	15	–	50	100	
$\overline{\text{Clear}}$ to Output, t_{PHL}	5	–	100	200	ns
	10	–	50	100	
	15	–	40	80	
Transition Time, t_{THL}, t_{TLH}	5	–	100	200	ns
	10	–	50	100	
	15	–	40	80	
Minimum Pulse Width, Clock, t_{WL}, t_{WH}	5	–	65	130	ns
	10	–	30	60	
	15	–	20	40	
$\overline{\text{Clear}}$, t_{WL}	5	–	50	100	ns
	10	–	25	50	
	15	–	20	40	
Minimum Data Setup Time, t_{SU}	5	–	20	40	ns
	10	–	10	20	
	15	–	0	10	
Minimum Data Hold Time, t_H	5	–	40	80	ns
	10	–	20	40	
	15	–	15	30	
Maximum Clock Frequency, f_{CL}	5	3.5	7	–	MHz
	10	6	12	–	
	15	8	16	–	
Maximum Clock Rise or Fall Time, t_rCL, t_fCL	5	15	–	–	μs
	10	15	–	–	
	15	15	–	–	
Input Capacitance, C_{IN} $\overline{\text{Clear}}$	–	–	25	40	pF
All other	–	–	5	7.5	
Minimum $\overline{\text{Clear}}$ Removal Time, t_{REM}	5	–	–40	0	ns
	10	–	–15	0	
	15	–	–10	0	

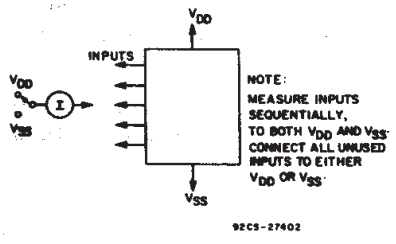


Fig. 12 – Input current test circuit.

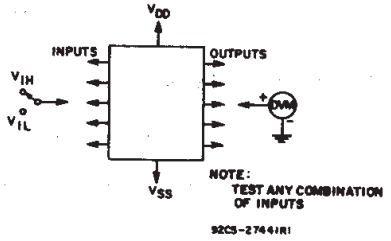
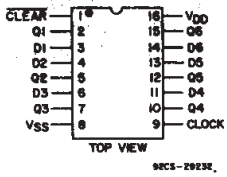


Fig. 13 – Input voltage test circuit.

TERMINAL ASSIGNMENT



PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead/Ball Finish (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
CD40174BE	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BEE4	ACTIVE	PDIP	N	16	25	Pb-Free (RoHS)	CU NIPDAU	N / A for Pkg Type	-55 to 125	CD40174BE	Samples
CD40174BF	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF	Samples
CD40174BF3A	ACTIVE	CDIP	J	16	1	TBD	A42	N / A for Pkg Type	-55 to 125	CD40174BF3A	Samples
CD40174BM	ACTIVE	SOIC	D	16	40	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BM96	ACTIVE	SOIC	D	16	2500	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174BM	Samples
CD40174BNSR	ACTIVE	SO	NS	16	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CD40174B	Samples
CD40174BPW	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM0174B	Samples
CD40174BPWE4	ACTIVE	TSSOP	PW	16	90	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-55 to 125	CM0174B	Samples

(1) The marketing status values are defined as follows:
ACTIVE: Product device recommended for new designs.
LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.
NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.
PREVIEW: Device has been announced but is not in production. Samples may or may not be available.
OBSOLETE: TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.
TBD: The Pb-Free/Green conversion plan has not been defined.
Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes.
Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.
Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

OTHER QUALIFIED VERSIONS OF CD40174B, CD40174B-MIL :

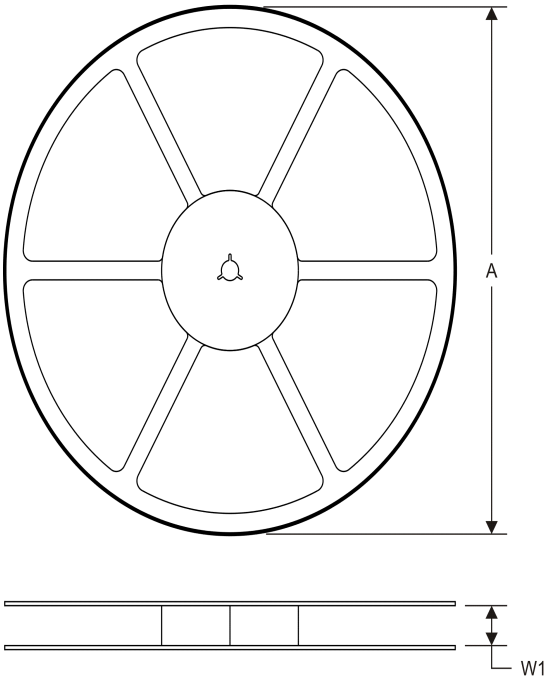
- Catalog: CD40174B
- Military: CD40174B-MIL

NOTE: Qualified Version Definitions:

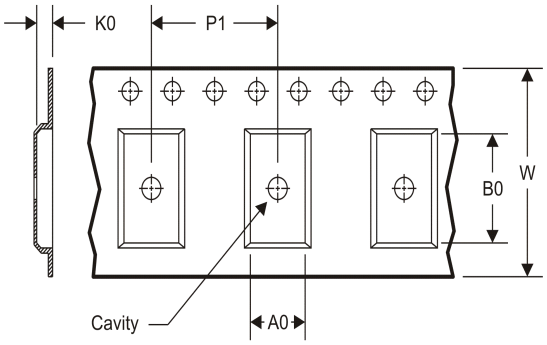
- Catalog - TI's standard catalog product
- Military - QML certified for Military and Defense Applications

TAPE AND REEL INFORMATION

REEL DIMENSIONS



TAPE DIMENSIONS



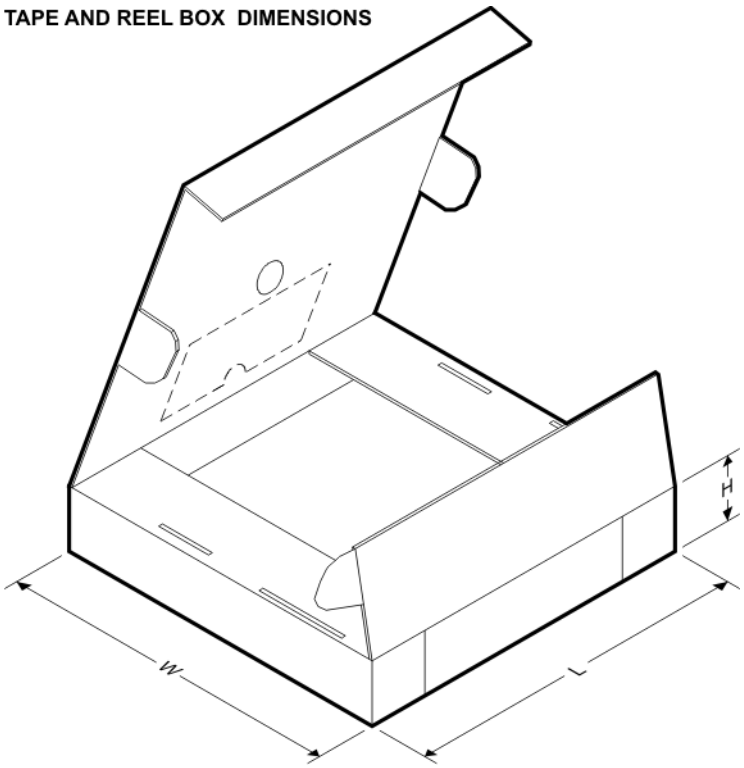
A0	Dimension designed to accommodate the component width
B0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

TAPE AND REEL INFORMATION

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD40174BM96	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
CD40174BNSR	SO	NS	16	2000	330.0	16.4	8.2	10.5	2.5	12.0	16.0	Q1

TAPE AND REEL BOX DIMENSIONS



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD40174BM96	SOIC	D	16	2500	333.2	345.9	28.6
CD40174BNSR	SO	NS	16	2000	367.0	367.0	38.0

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